

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Docket No: Q66584

Masayuki NAYA, et al.

Appln. No.: 10/053,585

Group Art Unit: 1641

Confirmation No.: 3468

Examiner: Christopher L. Chin

Filed: January 24, 2002

For: SURFACE PLASMON RESONANCE MEASURING CHIP AND METHOD OF  
MANUFACTURE THEREOF

EXCESS CLAIM FEE PAYMENT LETTER

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:


An Amendment Under 37 C.F.R. § 1.111 is attached hereto for concurrent filing in the above-identified application. The resulting excess claim fee has been calculated as shown below:

	After Amendment		Highest No. Previously Paid For						
All Claims	24	-	20	=	4	X	\$50.00	=	\$200.00
Independent	1	-	3	=		X	\$200.00	=	\$0.00
TOTAL								=	\$200.00

The statutory fee of \$200.00 is being charged to Deposit Account No. 19-4880 via EFS Payment Screen. The USPTO is also directed and authorized to charge all required fees, except for the Issue Fee and the Publication Fee, to Deposit Account No. 19-4880. Please also credit any overpayments to said Deposit Account.

Respectfully submitted,

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Date: August 10, 2007